

Docket No.: 57810-095

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
	:	
Yasuhiro TAKEDA, et al.	:	Confirmation Number:
	:	
Serial No.:	:	Group Art Unit:
	:	
Filed: March 30, 2004	:	Examiner:
	:	
For: SEMICONDUCTOR DEVICE AND METHOD OF FABRICATING SEMICONDUCTOR DEVICE		

INFORMATION DISCLOSURE STATEMENT

Mail Stop Information Disclosure
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The relevance of each non-English language reference, if any, is discussed in the present specification.

Serial No.:

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

A handwritten signature in black ink, appearing to read 'A. J. Steiner', written over the printed name.

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Date: March 30, 2004

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. 57810-095		SERIAL NO.	
(PTO-1449)						APPLICANT Yasuhiro TAKEDA, et al.			
						FILING DATE March 30, 2004		GROUP	
U.S. PATENT DOCUMENTS									
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear				
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FOREIGN PATENT DOCUMENTS									
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number + -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation			
						Yes	No		
		JP 5-102477 (w/ English Abstract)	04/23/1993	MATSUSHITA ELECTRIC IND. CO., LTD.					
		JP 2001-156291 A (w/ English Abstract)	06/08/2001	NEC CORP.					
		JP 2000-323710 A (w/ English Abstract)	11/24/2000	CHARTERED SEMICONDUCTOR MFG. LTD.					
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)									
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.							
EXAMINER					DATE CONSIDERED				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.